



Product/Process Change Notice - PCN 10_0349 Rev. -

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This notice is to inform you of a change that will be made to certain ADI products (see Material Report). Any issues with this PCN or requirements to qualify the change (additional data or samples) must be sent to ADI within 30 days of publication date. ADI contact information is listed below.

PCN Title: Metal Mask Revision and Datasheet Change for AD8280
Publication Date: 25-Apr-2011
Effectivity Date: 06-May-2011 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release

Description Of Change

Increase the self time from 700ms to 1s. With deglitch ON the minimum TESI width to held high will now be 1s. In Bypass deglitch mode the time will still be 50ms. This fix will prevent false failures in daisy chain operation while deglitch is ON.

Reason For Change

To eliminate race condition in self test logic when AD8280 is used in separate alarm mode and any deglitch setting ON.

Impact of the change (positive or negative) on fit, form, function & reliability

There will be no change to fit, form, or reliability. The only function that will change is the self test time, now ~1s.

Summary of Supporting Information

Qualification will be performed per AEC-Q100, Stress Test Qualification for Integrated Circuits. See attached Qualification Plan.

Supporting Documents

Attachment 1: Type: Qualification Plan Summary

ADI_PCN_10_0349_Rev_-_AD8280W_QP 9230_PCN.doc

For questions on this PCN, send email to the regional contacts below or contact your local ADI sales representative

Americas:	PCN_Americas@analog.com	Europe:	PCN_Europe@analog.com	Japan:	PCN_Japan@analog.com
				Rest of Asia:	PCN_ROA@analog.com

Appendix A - Affected ADI Models

Added Parts On This Revision - Product Family / Model Number (2)

AD8280 / AD8280WASTZ	AD8280 / AD8280WASTZ-RL
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Appendix B - Revision History

Rev	Publish Date	Rev Description
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